Abstracts

Automated phase noise measurement of Ku-band MMIC VCO on-wafer

J.M. Yang, D.C. Yang, P.G. Cheng and J.M. Dickson. "Automated phase noise measurement of Ku-band MMIC VCO on-wafer." 1999 MTT-S International Microwave Symposium Digest 99.4 (1999 Vol. IV [MWSYM]): 1763-1766 vol.4.

Voltage-controlled-oscillators (VCOs) are often used as low cost frequency sources in mmW transceivers. We have found that it is feasible to rapidly determine the phase noise of Ku-band VCOs on-wafer, using spectrum analyzers instead of special equipment, provided that external noises are suppressed and design is favorable. Our approach affords accurate and repeatable readings, obviates the need to rework at the module level, and results in significant production cost savings.

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